

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination NAKASE ET AL	
		Examiner Mark A. Williams	Art Unit 3676	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,923,751 A	07-1999	Ohtsuka et al.	379/433.13
	B	US-6,070,298 A	06-2000	Sorimachi, Akira	16/330
	C	US-6,148,480 A	11-2000	Cooke, Michael Paul	16/303
	D	US-6,678,539 B1	01-2004	Lu, Sheng-Nan	455/575.1
	E	US-5,987,122 A	11-1999	Daffara et al.	379/433.13
	F	US-5,398,378 A	03-1995	Lin, Chi-Chung	16/303
	G	US-6,829,807 B2	12-2004	Kim, Heung-Kee	16/322
	H	US-6,766,180 B2	07-2004	Doraiswamy et al.	455/575.1
	I	US-5,996,179 A	12-1999	Huong, Chin-Fu	16/330
	J	US-6,530,121 B2	03-2003	Hayashi, Ken	16/330
	K	US-6,459,887 B2	10-2002	Okuda, Tatsumi	455/90.1
	L	US-6,658,699 B2	12-2003	Huong, Chin-Fu	16/330
	M	US-2004/0245342 A1	12-2004	Cho et al.	235/472.01

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.